

ELECTRONIC INFORMATION DISCLOSURE STATEMENT

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Title of Invention	METHODOLOGY FOR MEASURING AND CONTROLLING FILM THICKNESS PROFILES																																												
<p>Application Number:</p> <p>Confirmation Number:</p> <p>First Named Applicant: Timothy Hayes</p> <p>Attorney Docket Number: BUR920020124US1</p> <p>Search string: (5375064 or 5628869 or 6030887 or 6211094).pn.</p> <p>US Patent Documents</p> <p>Note: Applicant is not required to submit a paper copy of cited US Patent Documents</p> <table border="1"><thead><tr><th>init</th><th>Cite.No.</th><th>Patent No.</th><th>Date</th><th>Patentee</th><th>Kind</th><th>Class</th><th>Subclass</th></tr></thead><tbody><tr><td></td><td>1</td><td>5375064</td><td>1994-12-20</td><td>Bollinger</td><td></td><td></td><td></td></tr><tr><td></td><td>2</td><td>5628869</td><td>1997-05-13</td><td>Malloon</td><td></td><td></td><td></td></tr><tr><td></td><td>3</td><td>6030887</td><td>2000-02-29</td><td>Desai et al</td><td></td><td></td><td></td></tr><tr><td></td><td>4</td><td>6211094</td><td>2001-04-03</td><td>Jun et al</td><td></td><td></td><td></td></tr></tbody></table> <p>Signature</p> <table border="1"><thead><tr><th>Examiner Name</th><th>Date</th></tr></thead><tbody><tr><td></td><td></td></tr></tbody></table>		init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass		1	5375064	1994-12-20	Bollinger					2	5628869	1997-05-13	Malloon					3	6030887	2000-02-29	Desai et al					4	6211094	2001-04-03	Jun et al				Examiner Name	Date		
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